

Docket No.: 91-P205-USA-G (756-151C1/CIP)

(0756-575)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Takashi INUSHIMA et al.) Group Art: 134

Serial No. 702,492

Filed: May 20, 1990

For: CVD APPARATUS) June 27, 1991

RECEIVED

REOUEST FOR CORRECTED RECEIPT

JUL 05 1991

APPLICATION BRANCH Commissioner of Patents

and Trademarks

Washington, D.C. 20231

Dear Sir: /

Attached is a copy of the Filing Receipt received from the Patent Office in the above application. continuing data for the above-identified application is incorrect as stated on the Filing Receipt. This application is a Continuation-in-part of Serial Number 07/497,794, filed 03/22/90 as stated on page 1 of the specification, a copy of which is attached hereto. It is therefore requested that a corrected receipt be issued.

Respectfully submitted,

Gerald

Regist fation No. 23,016

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CVD APPARATUS

Related Applications

This Application is a COntinuation-in-Part of copending Application Serial No. 07/497,794; which in turn is a Continuation of Application Serial No. 07/091,770, now abandoned.

Background of the Invention

The invention relates to a photo enhanced CVD apparatus.

Many chemical vapor deposition (CVD) processes are used, such as APCVD, LP CVD, plasma CVD, thermal CVD and so forth, for depositing a film on a substrate. While these processes have their own peculiar characteristics respectively, the temperature at which each process is carried out is commonly rather high. Such high temperature process is not suitable for formation of passivation film on an aluminum electrode arrangement.

Photo enhanced CVD process has attracted the interest of artisans because it can be carried out at a comparatively low temperature. This process is based on the energy of light, namely an optical reaction is carried out. For example, in the case of photo CVD process using silane and ammonia, mercury atoms are excited by irradiation of ultraviolet light of 2,537Å in wavelength. The process is carried out to deposit a silicon nitride film on a substrate in accordance with the following equation:

(484. 11-80)

FILING RECEIPT



UNITED STATES DEPARTMENT OF COMMERCE Patent and Trademar' * iffice ASSISTANT SECRETARY COMMISSIONER

OF PATENTS AND TRADE JARKS

Washington, D.C. 20231 0756 - 575

SERIAL NUMBER ./ FIL	IN DATE - GR	D ADTITUTE						
	115/5	FARIJUNIT	FIL	FEE REC'D	ATTORNEY DOCKET NO.	DRWGS	TOT CL	IND CL
07/702,492 05	/20/9691	184	\$	630.00	91-P205-USA-	/ 8	6	1

GERALD J. FERGUSON, JR. SIXBEY, FRIEDMAN, LEEDOM & FERGUSON 2010 CORPORATE RIDGE, STE. 600 MCLEAN, VA 22102

Receipt is acknowledged of the patent application identified herein. It will be considered in its order and you will be notified as to the examination thereof. Be sure to give the U.S. SERIAL NUMBER, DATE OF FILING, NAME OF APPLICANT, and TITLE OF INVENTION when inquiring about this application. Fees transmitted by check or draft are subject to collection. Please verify the accuracy of the data presented on this transmittal.

Applicant(s)

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CONTINUING DATA AS CLAIMED BY APPLICANT-

THIS APPLN IS A DIV OF 07/497,794 03/22/90 WHICH IS A CON OF 07/091,770 09/01/87

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FOREIGN/PCT APPLICATIONS-JAPAN

JAPAN JAPAN JAPAN 61-213323 61-213324 61-213325 09/09/86 09/09/86

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TITLE CVD APPARATUS

PRELIMINARY CLASS: 118

